FDP6676S / FDB6676S 30V N-Channel PowerTrench[®] SyncFET[™] Features This MOSFET is designed to replace a single MOSFET • 38 A, 30 V. $R_{DS(ON)} = 6.5 \text{ m}\Omega @ V_{GS} = 10 \text{ V}$ and parallel Schottky diode in synchronous DC:DC $R_{DS(ON)} = 8.0 \text{ m}\Omega @ V_{GS} = 4.5 \text{ V}$ power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low • Includes SyncFET Schottky body diode $R_{\text{DS}(\text{ON})}$ and low gate charge. The FDP/B6676S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDP/B6676S as the low-side switch in a • Low gate charge (40nC typical) synchronous rectifier is indistinguishable from the High performance trench technology for extremely performance of the FDP/B6676 in parallel with a low R_{DS(ON)} and fast switching High power and current handling capability D D

TO-263AB

FDB Series



TO-220

FDP Series

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±16	V
ID	Drain Current – Continuous	(Note 1)	76	A
	- Pulsed	(Note 1)	150	
PD	Total Power Dissipation @ T _c = 25°C		70	W
	Derate above 25°C		0.56	W/°C
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C
Τ _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		275	°C
Therma	I Characteristics			
R _{eJC}	Thermal Resistance, Junction-to-Case		1.8	°C/W
R _{eja}	Thermal Resistance, Junction-to-Ambient		55	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDB6676S	FDB6676S	13"	24mm	800
FDP6676S	FDP6676S	Tube	n/a	45

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October 2001



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General Description

Schottky diode.

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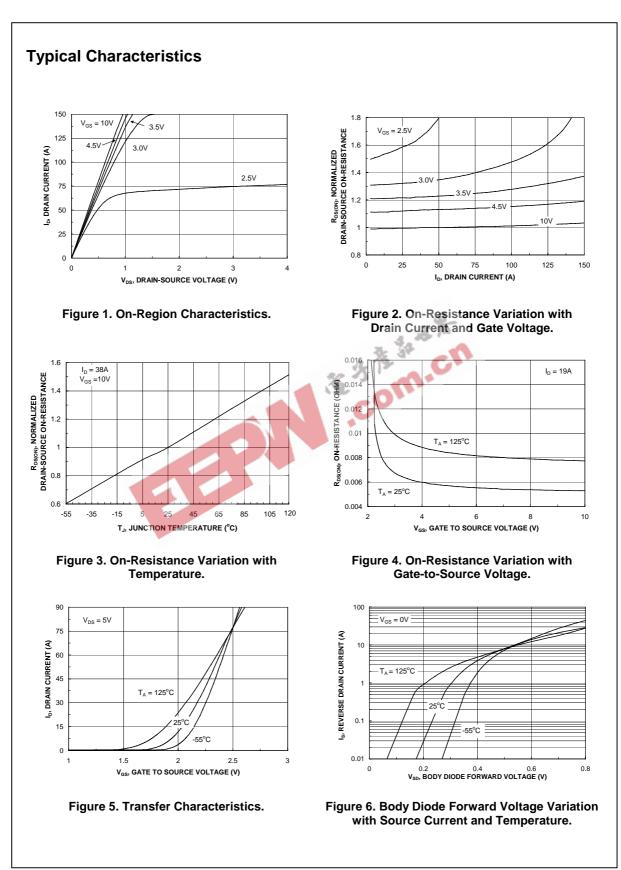
D S

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
-				тур	IVIAX	Units
	ource Avalanche Ratings (Note		1	1		
W _{DSS}	Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 25 \text{ V}$, $I_D = 12 \text{ A}$			310	mJ
AR	Drain-Source Avalanche Current				12	A
Off Char	acteristics					
BV_{DSS}	Drain–Source Breakdown Voltage	$V_{GS} = 0 V$, $I_D = 1 mA$	30			V
<u>ΔBV_{DSS}</u> ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to $25^{\circ}C$		25		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 24 \text{ V}, V_{GS} = 0 \text{ V}$			500	μA
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = 16 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -16 V$ $V_{DS} = 0 V$			-100	nA
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$	1	1.3	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C		-8.4		mV/°C
R _{DS(on)}	Static Drain–Source	$V_{GS} = 10 \text{ V}, \qquad I_D = 38 \text{ A}$	129	4.7	6.5	mΩ
	On-Resistance	$V_{GS} = 4.5 \text{ V}, \qquad I_D = 35 \text{ A}$	2	5.2	8.0	
		V_{GS} =10 V, I_D =38A, T_J =125°C	5 M T	7.3	11	
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	60			А
g _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_D = 38 \text{ A}$		145		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 15 V$, $V_{GS} = 0 V$,		4853		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		850		pF
C _{rss}	Reverse Transfer Capacitance			316		pF
Switchin	ng Characteristics (Note 2)					
t _{d(on)}	Turn–On Delay Time	$V_{DS} = 15 V$, $I_{D} = 1 A$,		14	25	ns
t _r	Turn–On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		11	20	ns
t _{d(off)}	Turn-Off Delay Time			89	142	ns
t _f	Turn–Off Fall Time			31	50	ns
Qg	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 38 \text{ A},$		40	56	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 V$		10		nC
Q _{gd}	Gate-Drain Charge			11		nC
	ource Diode Characteristics	and Maximum Ratings				
V _{SD}	Drain–Source Diode Forward Voltage	$ \begin{array}{c} V_{GS} = 0 \ V, I_S = 3.5 \ A (\text{Note 1}) \\ V_{GS} = 0 \ V, I_S = 7 \ A (\text{Note 1}) \end{array} $		0.4 0.5	0.7	V
t _{rr}	Diode Reverse Recovery Time	$I_F = 3.5 \text{ A},$ (Note 1)	1	28.5		nS
		$d_{iF}/d_t = 300 \text{ A}/\mu \text{s}$ (Note 2)	1		1	-

Notes:

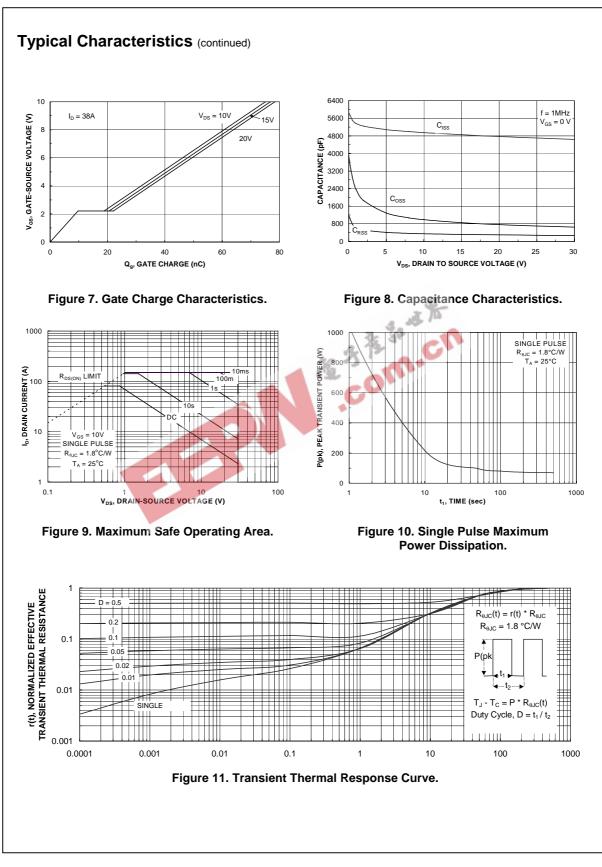
Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%
See "SyncFET Schottky body diode characteristics" below.

FDP6676S/FDB6676S



FDP6676S/FDB6676S

FDP6676S/FDB6676S Rev C (W)



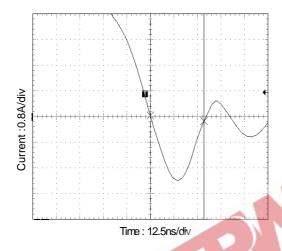
FDP6676S/FDB6676S

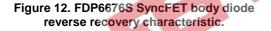
FDP6676S/FDB6676S Rev C (W)

Typical Characteristics (continued)

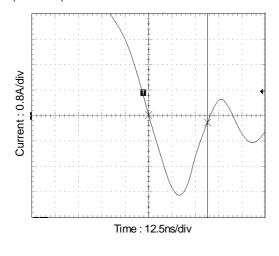
SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 FDP6676S.





For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDP6676).





Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

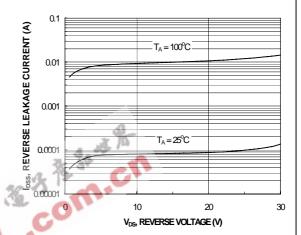


Figure 14. SyncFET diode reverse leakage versus drain-source voltage and temperature.

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